# MSKSEMI 美森科













**ESD** 

155

MOV

GDT

PLED

**AON6312-MS** 

**Product specification** 





#### **Description**

The AON6312-MS uses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **Features**

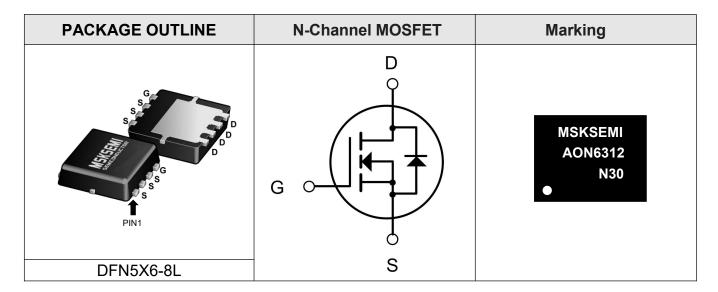
VDS = 30V ID =150A

RDS(ON) < 2.4m $\Omega$  VGS=10V

## **Application**

- Battery protection
- Load switch
- Uninterruptible power supply

#### **Reference News**



## Absolute Maximum Ratings (TC=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	30	V
Vgs	Gate-Source Voltage	±20	V
In @Tc=25°C	Continuous Drain Current, V gs @ 10V <sup>1</sup>	150	Α
In @Tc=100°C	Continuous Drain Current, V gs @ 10V 1	80	Α
Ірм	Pulsed Drain Current <sup>2</sup>	160	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	180	mJ
las	Avalanche Current	60	Α
PD@Tc=25°C	Total Power Dissipation <sup>4</sup>	187	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	Û
Reja	Thermal Resistance Junction-Ambient <sup>1</sup>	62	°C/ W
Rejc	Thermal Resistance Junction- Case <sup>1</sup>	1.1	°C/ W



# Electrical Characteristics (TJ=25 ℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=250uA	30			V	
△ BVDSS/ △ TJ	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.014		V/ °C	
Dagger	Chatia Basia Course On Basiatan 2	V <sub>G</sub> s=10V , I <sub>D</sub> =30A		2	2.4	0	
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>G</sub> s=4.5V , I <sub>D</sub> =15A		2.5	3.2	mΩ	
VGS(th)	Gate Threshold Voltage	\\\\-\-\-\-\-\-\-\-\-\-\-\-\-\-\-\-	1.2		2.5	V	
△ VGS(th)	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>G</sub> s=V <sub>D</sub> s , I <sub>D</sub> =250uA		-4		Mv/°C	
1	Drain Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA	
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA	
Igss	Gate-Source Leakage Current	kage Current V <sub>GS</sub> = ±20V , V <sub>DS</sub> =0V			±100	nA	
gfs	Forward Transconductance V <sub>DS</sub> =5V , I <sub>D</sub> =30A			50		S	
Rg	Gate Resistance V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz			1.7		Ω	
Qg	Total Gate Charge (4.5V)			56.9			
Qgs	Gate-Source Charge	Vps=15V , Vgs=10V , Ip=15A		13.8		nC	
Qgd	Gate-Drain Charge			23.5		1	
Td(on)	Turn-On Delay Time			20.1			
Tr	Rise Time	V <sub>DD</sub> =15V , V <sub>GS</sub> =10V , R <sub>G</sub> =3.3Ω		6.3			
T <sub>d(off)</sub>	Turn-Off Delay Time	, I <sub>D</sub> =1A		124.6		ns	
Tf	Fall Time			15.8			
Ciss	Input Capacitance			4345			
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		340		pF	
Crss	Reverse Transfer Capacitance			225			

#### **Diode Characteristics**

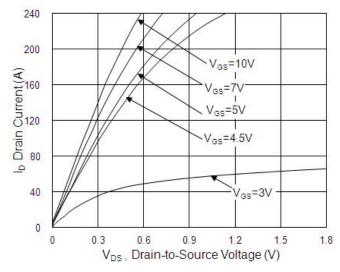
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current <sup>1,6</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			150	Α
Vsp	Diode Forward Voltage <sup>2</sup>	Vgs=0V , Is=1A , TJ=25°C			1.2	V

#### Note:

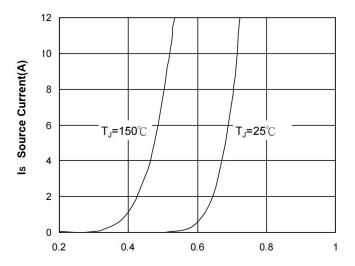
- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq ~~300 \text{us}$  , duty cycle  $\leq ~~2\%$
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V, L=0. 1mH,  $I_{AS}$ =60A
- 4. The power dissipation is limited by 1500 junction temperature
- 5. The data is theoretically the same as  $I_{\text{D}}$  and  $I_{\text{DM}}\;$  , in real applications , should be limited by total power dissipation.
- 6. Package limitation current is 85A.



# **Typical Electrical and Thermal Characteristics**



**Fig.1 Typical Output Characteristics** 



V<sub>SD</sub> , Source-to-Drain Voltage (V)

Fig. 3 Forward Characteristics of Reverse

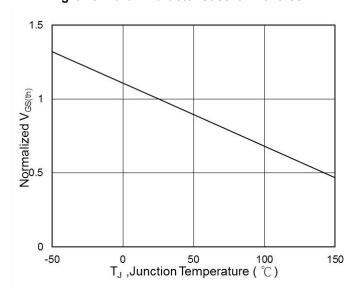


Fig.5NormalizedVgs(th)v.s TJ

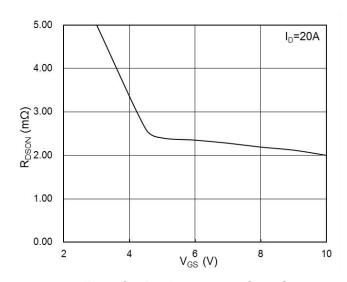


Fig.2 On-Resistance v.s Gate-Source

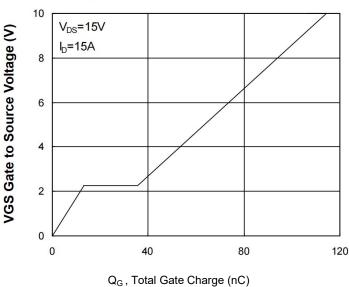


Fig. 4 Gate-Charge Characteristics

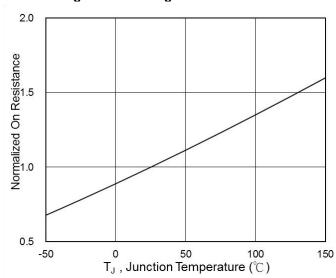
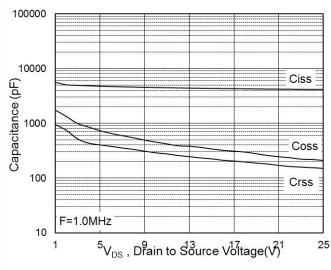


Fig.6Normalized RDSONV.S TJ





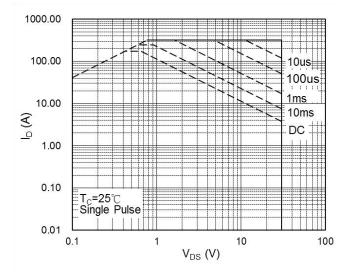
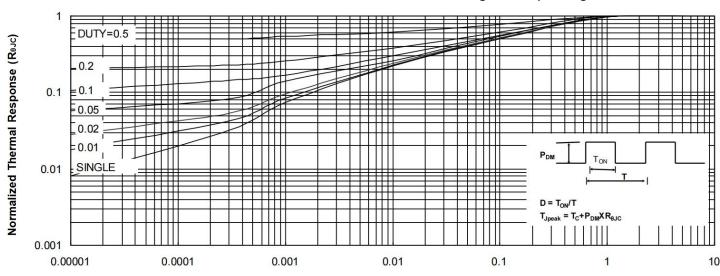


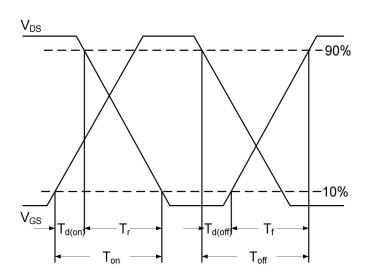
Fig.7 Capacitance

Fig.8Safe Operating Area



t, Pulse Width (s)

Fig. 9 Normalized Maximum Transient Thermal Impedance



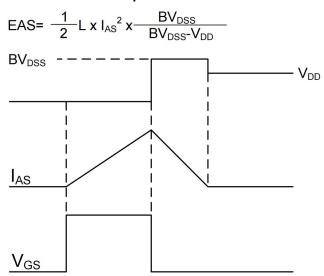
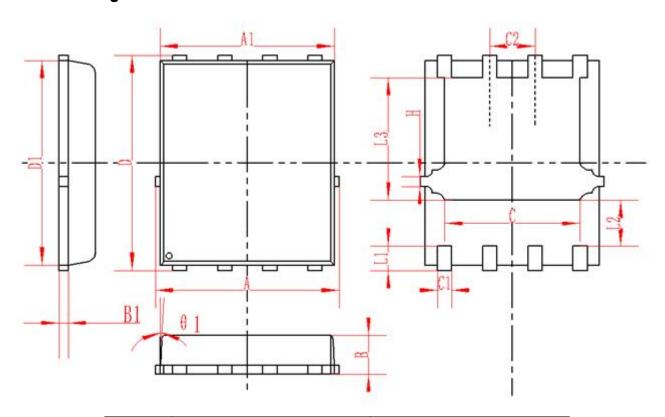


Fig.10 Switching Time Waveform

Fig.11 Unclamped Inductive Switching Waveform



# DFN5X6-8L Package Information



SYMBOL		MM			INCH		
STIVIDUL	MIN	NOM	MAX	MIN	NOM	MAX	
А	4.95	5	5.05	0.195	0.197	0.199	
A1	4.82	4.9	4.98	0.190	0.193	0.196	
D	5.98	6	6.02	0.235	0.236	0.237	
D1	5.67	5.75	5.83	0.223	0.226	0.230	
В	0.9	0.95	1	0.035	0.037	0.039	
B1	0.254REF			0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159	
C1	0.35	0.4	0.45	0.014	0.016	0.018	
C2	1.27TYP			0.5TYP			
θ1	8。	10 <sub>°</sub>	12 <sub>°</sub>	8。	10 <sub>°</sub>	12。	
L1	0.63	0.64	0.65	0.025	0.025	0.026	
L2	1.2	1.3	1.4	0.047	0.051	0.055	
L3	3.415	3.42	3.425	0.134	0.135	0.135	
Н	0.24	0.25	0.26	0.009	0.010	0.010	

## **REEL SPECIFICATION**

P/N	PKG	QTY
AON6312-MS	DFN5X6-8L	5000



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